

Microscopic characterization activity at CERN

Tuesday 20 June 2023 16:25 (30 minutes)

The microscopy team at CERN is devoted to providing material characterization including topographical imaging, morphology, phase identification and chemical analysis through the utilization of Scanning Electron Microscopy (SEM), Focused Ion Beam (FIB)-SEM and X-ray Diffraction (XRD).

Material characterization is carried out on a wide range of materials with emphasis on metals and alloys, which display great compatibility with electron microscopy apparatus, along with ceramics, composites and thin film specimens. We will present specific examples of how these techniques are utilized to extract the maximum possible information from samples that are either being installed or extracted from the detectors and accelerator complex.

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Session Classification: Manipulation